Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | TSUCHIYA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-5,932,492	08-1999	Hahm et al.	-
X	В	US-6,204,070 B1	03-2001	Kim, Young Bog	-
X	С	US-6,211,079 B1	04-2001	Jenq, J. S. Jason	-
X	D	US-6,342,712 B1	01-2002	Miki et al.	-
X	Е	US-6,559,003 B2	05-2003	Hartner et al.	-
X	F	US-2002/0196653 A1	12-2002	Kim et al.	-
	G	US-			
	Н	US-			
	Ι	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	· 0					
	Р			-		
	σ					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	W							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.